

Notice of References Cited	Application/Control No. 10/551,900		Applicant(s)/Patent Under Reexamination YASUO ET AL.	
	Examiner Mark Kopec		Art Unit 1796	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2004/0157747	08-2004	Chen et al.	505/238
*	B	US-6,649,570	11-2003	Belouet, Christian	505/237
*	C	US-5,595,960	01-1997	Belouet et al.	505/473
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	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Thiele et al "Grain boundaries in YBa ₂ Cu ₃ O ₇ films grown on bicrystalline Ni substrates", Physica C 355 (2001) 203-210
	V	Wu et al "Epitaxial Layers and Bilayers of Ce Oxide...", Proceedings of 6th Int. Workshp. on Oxide Elect., College Park, Mdm Dec 6-7 1999 (Abstract Only).
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.